Application/Control No. Applicant(s)/Patent Under Reexamination 10/062,193 TEIG ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Phallaka Kik 2825 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,735,748 05-2004 Teig et al. 716/5 Α US-В US-С US-D US-Е US-F US-G US-US-1 US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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